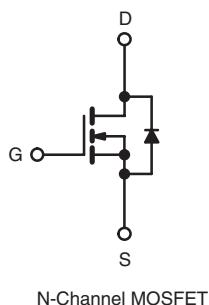


Power MOSFET

PRODUCT SUMMARY		
V _{DS} (V)	60	
R _{DS(on)} (Ω)	V _{GS} = 5.0 V	0.028
Q _g (Max.) (nC)	66	
Q _{gs} (nC)	12	
Q _{gd} (nC)	43	
Configuration	Single	



ORDERING INFORMATION

Package	SMD-220	SMD-220	SMD-220
Lead (Pb)-free	IRLZ44SPbF SiHLZ44S-E3	IRLZ44STRRPbFa SiHLZ44STR-E3a	- -
SnPb	IRLZ44S SiHLZ44S	IRLZ44STRR ^a SiHLZ44STR ^a	IRLZ44STRL ^a SiHLZ44STL ^a

Note

a. See device orientation.

ABSOLUTE MAXIMUM RATINGS T_C = 25 °C, unless otherwise noted

PARAMETER	SYMBOL	LIMIT	UNIT
Drain-Source Voltage	V _{DS}	60	V
Gate-Source Voltage	V _{GS}	± 10	
Continuous Drain Current ^f	I _D	50	A
Continuous Drain Current		36	
Pulsed Drain Current ^a	I _{DM}	200	
Linear Derating Factor		1.0	W/°C
Linear Derating Factor (PCB Mount) ^e		0.025	
Single Pulse Avalanche Energy ^b	E _{AS}	400	mJ
Maximum Power Dissipation	P _D	150	W
Maximum Power Dissipation (PCB Mount) ^e		3.7	
Peak Diode Recovery dV/dt ^c	dV/dt	4.5	V/ns
Operating Junction and Storage Temperature Range	T _J , T _{stg}	- 55 to + 175	°C
Soldering Recommendations (Peak Temperature) ^d	for 10 s	300 ^d	

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. V_{DD} = 25 V, starting T_J = 25 °C, L = 179 μH, R_G = 25 Ω, I_{AS} = 51 A (see fig. 12).

c. I_{SD} ≤ 51 A, dI/dt ≤ 250 A/μs, V_{DD} ≤ V_{DS}, T_J ≤ 175 °C.

d. 1.6 mm from case.

e. When mounted on 1" square PCB (FR-4 or G-10 material).

f. Current limited by the package, (Die Current = 51 A).

* Pb containing terminations are not RoHS compliant, exemptions may apply



RoHS*
COMPLIANT

THERMAL RESISTANCE RATINGS

PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R_{thJA}	-	62	$^{\circ}\text{C}/\text{W}$
Maximum Junction-to-Ambient (PCB Mount) ^a	R_{thJA}	-	40	
Maximum Junction-to-Case (Drain)	R_{thJC}	-	1.0	

Note

a. When mounted on 1" square PCB (FR-4 or G-10 material).

SPECIFICATIONS $T_J = 25 \text{ }^{\circ}\text{C}$, unless otherwise noted

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}$, $I_D = 250 \mu\text{A}$		60	-	-	V
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference to $25 \text{ }^{\circ}\text{C}$, $I_D = 1 \text{ mA}$		-	0.070	-	$^{\circ}\text{C}/\text{V}$
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = 250 \mu\text{A}$		1.0	-	2.0	V
Gate-Source Leakage	I_{GSS}	$V_{GS} = \pm 10 \text{ V}$		-	-	± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 60 \text{ V}$, $V_{GS} = 0 \text{ V}$		-	-	25	μA
		$V_{DS} = 48 \text{ V}$, $V_{GS} = 0 \text{ V}$, $T_J = 150 \text{ }^{\circ}\text{C}$		-	-	250	
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS} = 5.0 \text{ V}$	$I_D = 31 \text{ A}^b$	-	-	0.028	Ω
		$V_{GS} = 4.0 \text{ V}$	$I_D = 25 \text{ A}^b$	-	-	0.039	
Forward Transconductance	g_{fs}	$V_{DS} = 25 \text{ V}$, $I_D = 31 \text{ A}^b$		23	-	-	S
Dynamic							
Input Capacitance	C_{iss}	$V_{GS} = 0 \text{ V}$, $V_{DS} = 25 \text{ V}$, $f = 1.0 \text{ MHz}$, see fig. 5		-	3300	-	pF
Output Capacitance	C_{oss}			-	1200	-	
Reverse Transfer Capacitance	C_{rss}			-	200	-	
Total Gate Charge	Q_g	$V_{GS} = 5.0 \text{ V}$	$I_D = 51 \text{ A}$, $V_{DS} = 48 \text{ V}$, see fig. 6 and 13 ^b	-	-	66	nC
Gate-Source Charge	Q_{gs}			-	-	12	
Gate-Drain Charge	Q_{gd}			-	-	43	
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = 30 \text{ V}$, $I_D = 51 \text{ A}$, $R_G = 4.6 \Omega$, $R_D = 0.56 \Omega$, see fig. 10 ^b		-	17	-	ns
Rise Time	t_r		-	230	-		
Turn-Off Delay Time	$t_{d(off)}$		-	42	-		
Fall Time	t_f		-	110	-		
Internal Drain Inductance	L_D	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	nH
Internal Source Inductance	L_S			-	7.5	-	
Drain-Source Body Diode Characteristics							
Continuous Source-Drain Diode Current	I_S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	50 ^c	A
Pulsed Diode Forward Current ^a	I_{SM}			-	-	200	
Body Diode Voltage	V_{SD}	$T_J = 25 \text{ }^{\circ}\text{C}$, $I_S = 51 \text{ A}$, $V_{GS} = 0 \text{ V}^b$		-	-	2.5	V
Body Diode Reverse Recovery Time	t_{rr}	$T_J = 25 \text{ }^{\circ}\text{C}$, $I_F = 51 \text{ A}$, $dI/dt = 100 \text{ A}/\mu\text{s}^b$		-	130	180	ns
Body Diode Reverse Recovery Charge	Q_{rr}			-	0.84	1.3	μC
Forward Turn-On Time	t_{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D)					

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. Pulse width $\leq 300 \mu\text{s}$; duty cycle $\leq 2 \%$.

c. Current limited by the package, (Die Current = 51 A).

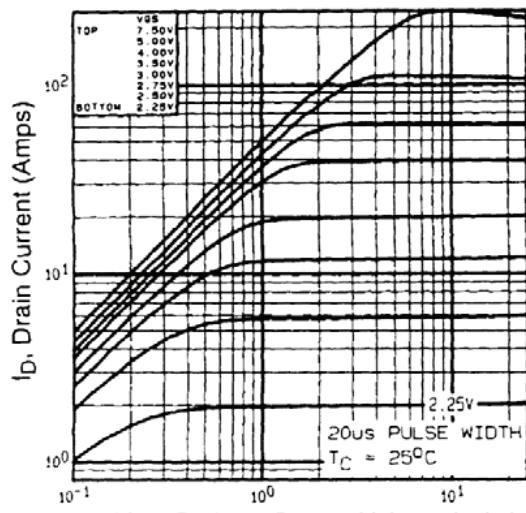
TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted


Fig. 1 - Typical Output Characteristics, $T_C = 25\text{ }^\circ\text{C}$

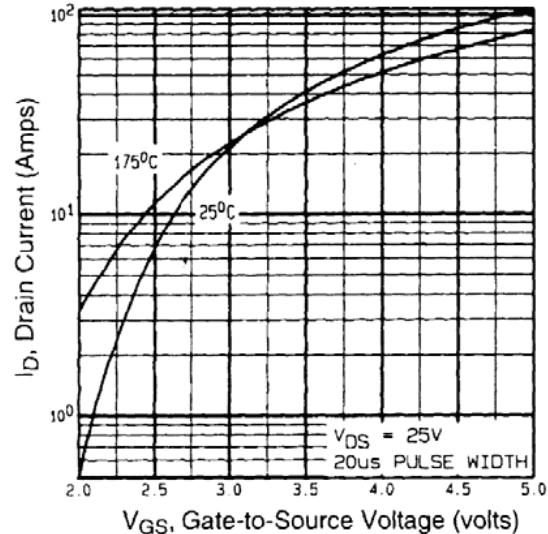


Fig. 3 - Typical Transfer Characteristics

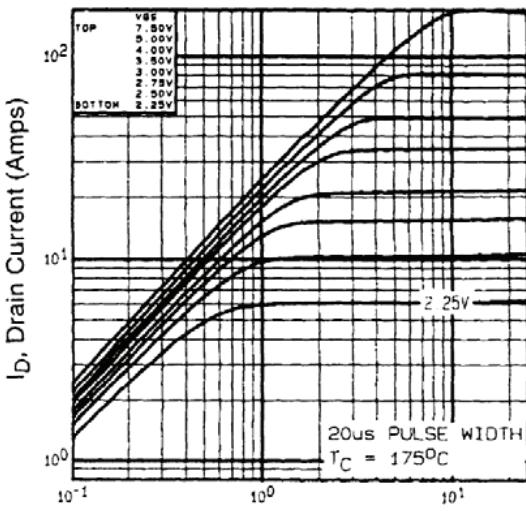


Fig. 2 - Typical Output Characteristics, $T_C = 150\text{ }^\circ\text{C}$

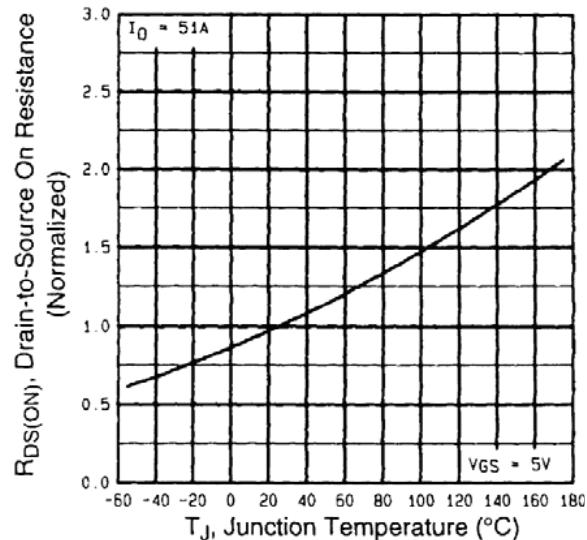


Fig. 4 - Normalized On-Resistance vs. Temperature

IRLZ44S, SiHLZ44S

Vishay Siliconix

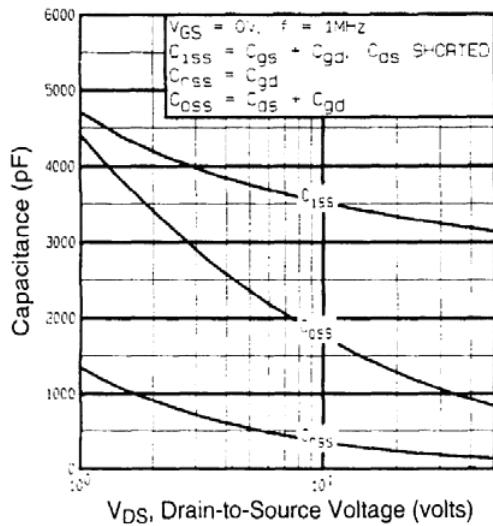


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

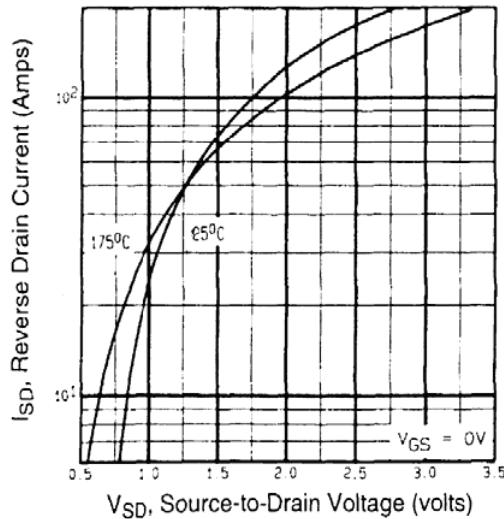


Fig. 7 - Typical Source-Drain Diode Forward Voltage

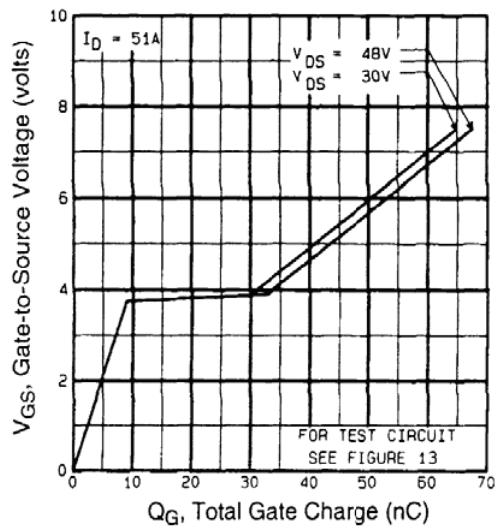


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

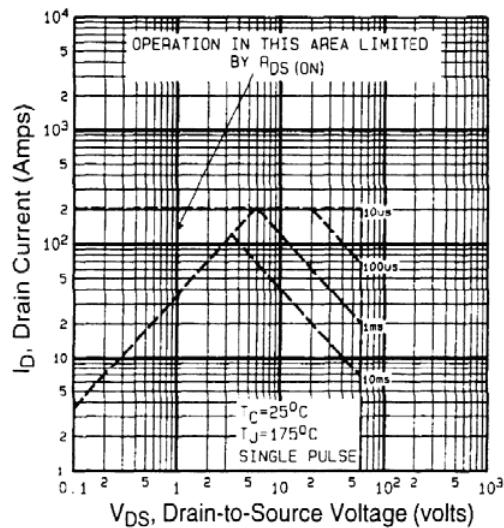


Fig. 8 - Maximum Safe Operating Area

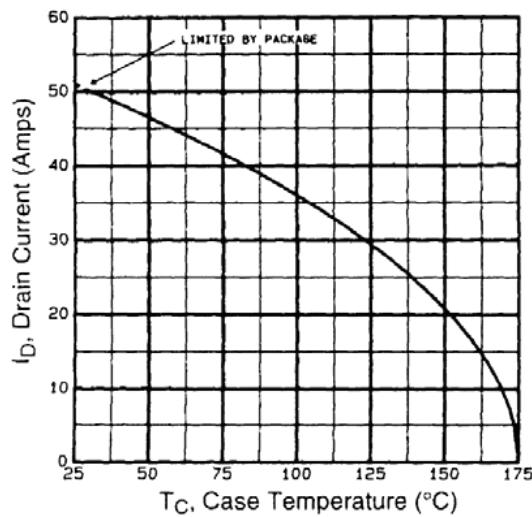


Fig. 9 - Maximum Drain Current vs. Case Temperature

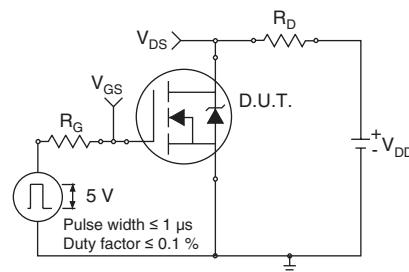


Fig. 10a - Switching Time Test Circuit

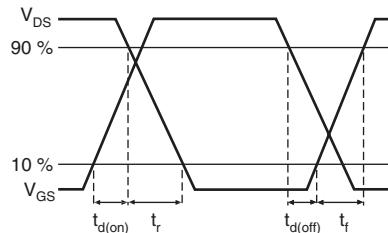


Fig. 10b - Switching Time Waveforms

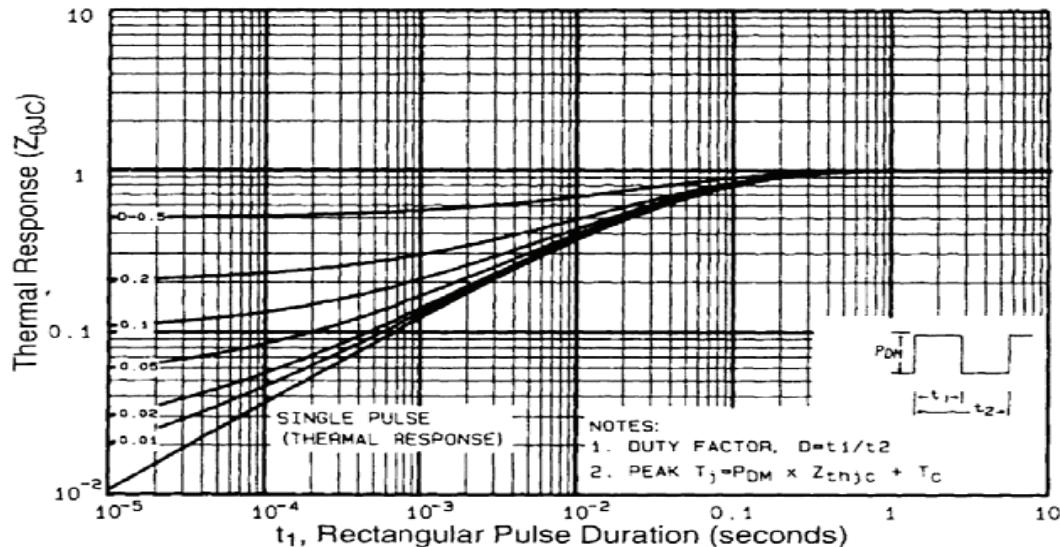


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

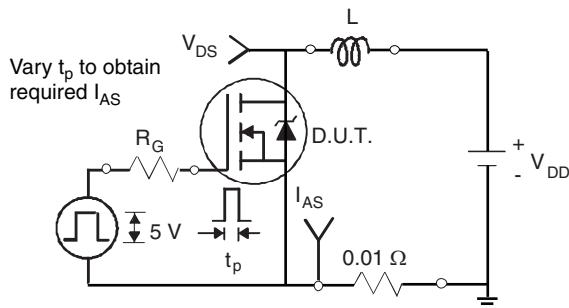


Fig. 12a - Unclamped Inductive Test Circuit

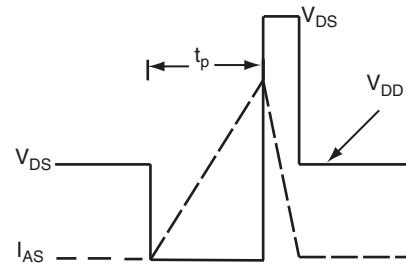


Fig. 12b - Unclamped Inductive Waveforms

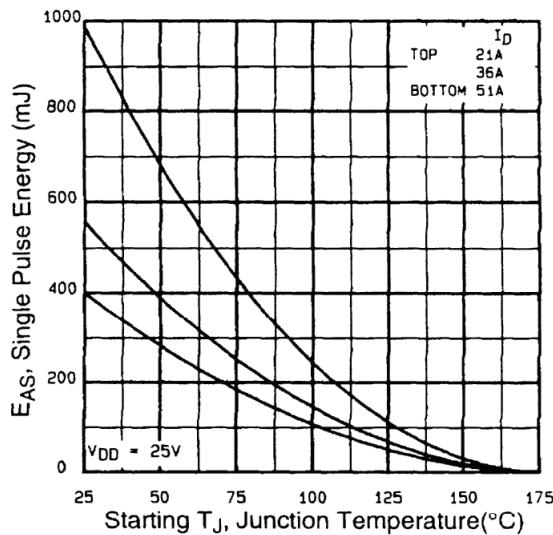


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

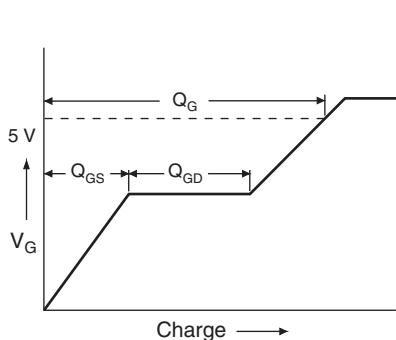


Fig. 13a - Basic Gate Charge Waveform

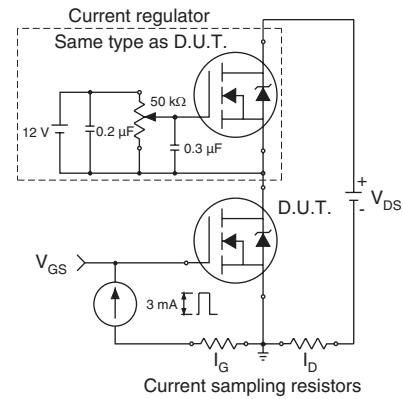
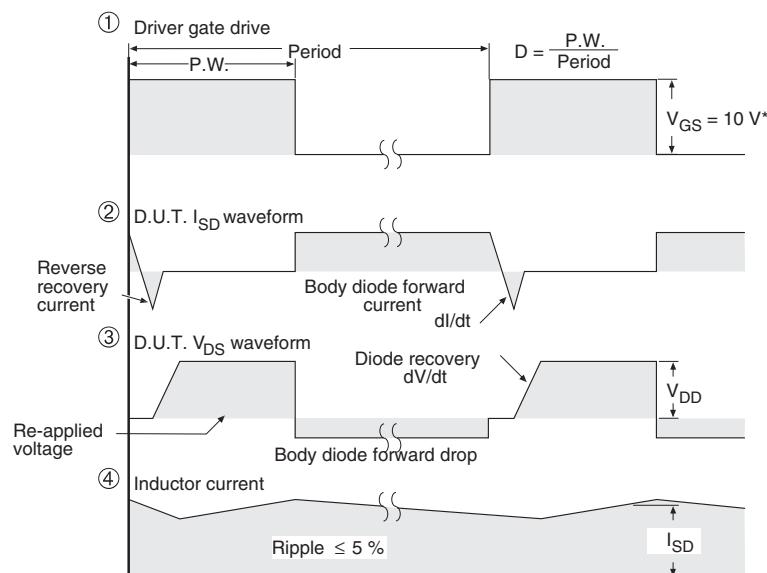
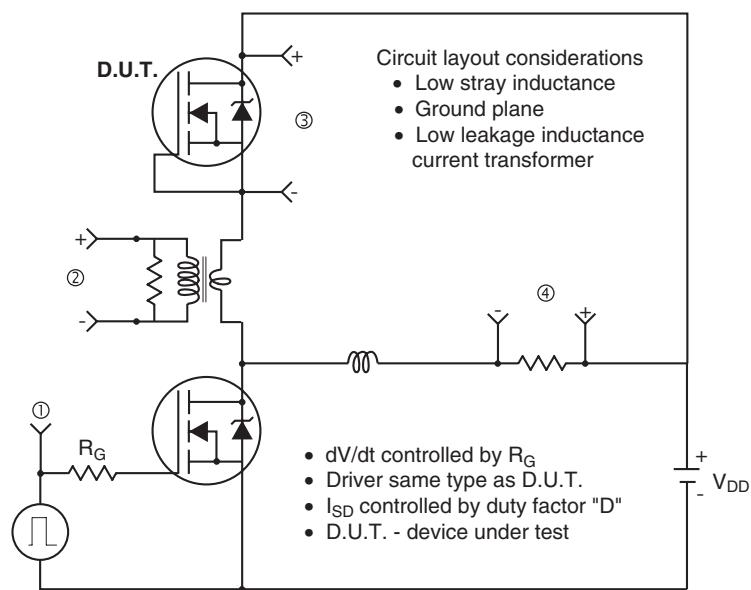


Fig. 13b - Gate Charge Test Circuit

Peak Diode Recovery dV/dt Test Circuit



* $V_{GS} = 5 \text{ V}$ for logic level devices

Fig. 14 - For N-Channel

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